

#### FEATURES

- High Current Transfer Ratios
  - at 10 mA: 40–320%
  - at 1.0 mA: 45% typical (>13)
- Low CTR Degradation
- Good CTR Linearity Depending on Forward Current
- Isolation Test Voltage, 5300 V<sub>RMS</sub>
- High Collector-emitter Voltage, V<sub>CEO</sub>=70 V
- Low Saturation Voltage
- Fast Switching Times
- Field-effect Stable by TRIOS (TRansparent IOn Shield)
- Temperature Stable
- Low Coupling Capacitance
- End-Stackable, .100" (2.54 mm) Spacing
- High Common-Mode Interference Immunity (Unconnected Base)
- Underwriters Lab File #52744
- VDE 0884 Available with Option 1
- SMD Option, See SFH6206 Data Sheet

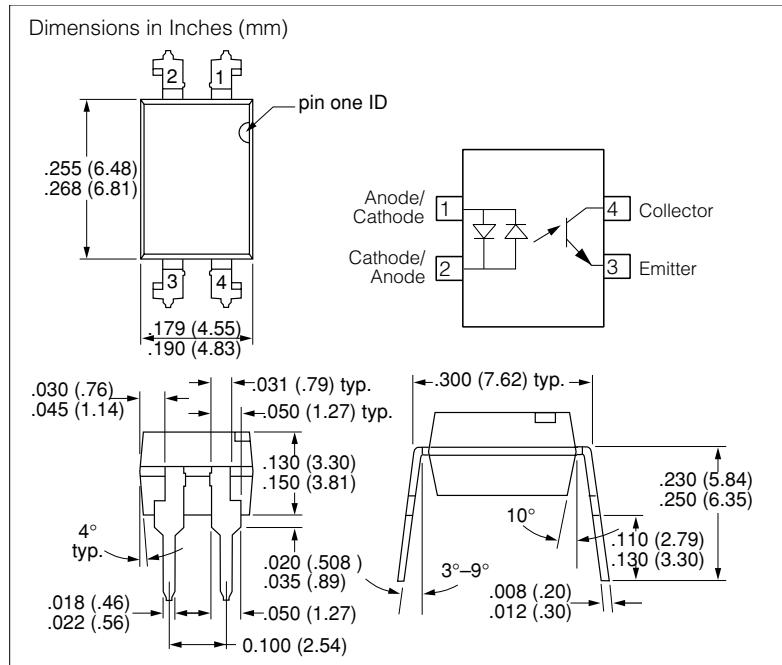
#### DESCRIPTION

The SFH620A features a high current transfer ratio, low coupling capacitance and high isolation voltage. These couplers have a GaAs infrared emitting diode emitter, which is optically coupled to a silicon planar phototransistor detector, and is incorporated in a plastic DIP-4 package.

The coupling devices are designed for signal transmission between two electrically separated circuits.

The couplers are end-stackable with 2.54 mm lead spacing.

Creepage and clearance distances of >8.0 mm are achieved with option 6. This version complies with IEC 950 (DIN VDE 0805) for reinforced insulation up to an operation voltage of 400 V<sub>RMS</sub> or DC.



#### Maximum Ratings

##### Emitter

Reverse Voltage.....	6.0 V
DC Forward Current.....	±60 mA
Surge Forward Current (t <sub>p</sub> ≤10 μs) .....	±2.5 A
Total Power Dissipation.....	100 mW

##### Detector

Collector-emitter Voltage .....	70 V
Emitter-collector Voltage.....	7.0 V
Collector Current .....	50 mA
Collector Current (t <sub>p</sub> ≤1.0 ms).....	100 mA
Total Power Dissipation.....	150 mW

##### Package

Isolation Test Voltage between Emitter and Detector, refer to Climate DIN 40046, part 2, Nov. 74.....	5300 V <sub>RMS</sub>
Creepage.....	≥7.0 mm
Clearance .....	≥7.0 mm
Insulation Thickness between Emitter and Detector .....	≥0.4 mm
Comparative Tracking Index per DIN IEC 112/VDEO 303, part 1 .....	175
Isolation Resistance	
V <sub>IO</sub> =500 V, T <sub>A</sub> =25°C .....	≥10 <sup>12</sup> Ω
V <sub>IO</sub> =500 V, T <sub>A</sub> =100°C .....	≥10 <sup>11</sup> Ω
Storage Temperature Range .....	-55 to +150°C
Ambient Temperature Range.....	-55 to +100°C
Junction Temperature .....	100°C
Soldering Temperature (max. 10 s. Dip Soldering Distance to Seating Plane ≥1.5 mm).....	260°C

**Characteristics ( $T_A=25^\circ\text{C}$ )**

Description	Symbol		Unit	Condition
<b>Emitter</b>				
Forward Voltage	$V_F$	1.25 ( $\leq 1.65$ )	V	$I_F=\pm 60 \text{ mA}$
Capacitance	$C_0$	50	pF	$V_R=0 \text{ V}, f=1.0 \text{ MHz}$
Thermal Resistance	$R_{\text{thJA}}$	750	K/W	—
<b>Detector</b>				
Capacitance	$C_{CE}$	6.8	pF	$V_{CE}=5.0 \text{ V}, f=1.0 \text{ MHz}$
Thermal Resistance	$R_{\text{thJA}}$	500	K/W	—
<b>Package</b>				
Collector-emitter Saturation Voltage	$V_{CEsat}$	0.25 ( $\leq 0.4$ )	V	$I_F=10 \text{ mA}, I_C=2.5 \text{ mA}$
Coupling Capacitance	$C_C$	0.2	pF	—

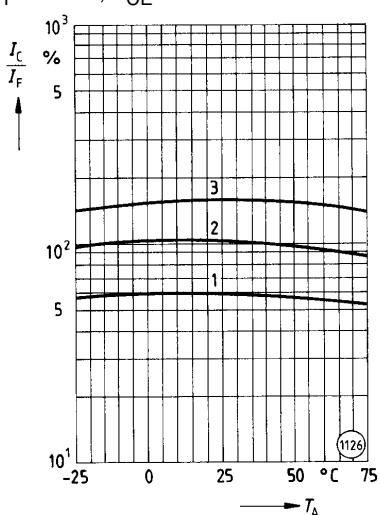
Note: Still air, coupler soldered to PCB or base.

**Current Transfer Ratio ( $I_C/I_F$  at  $V_{CE}=5.0 \text{ V}$ ) and Collector-emitter Leakage Current by Dash Number**

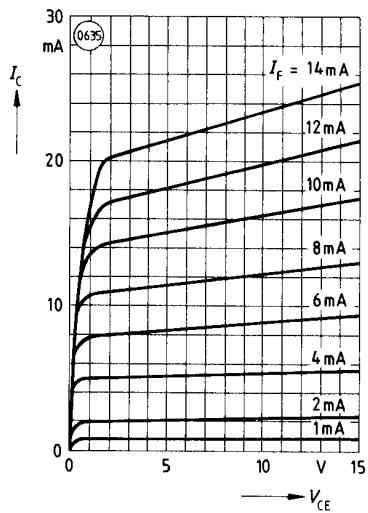
Description	-1	-2	-3	
$I_C/I_F$ ( $I_F=\pm 10 \text{ mA}$ )	40–125	63–200	100–320	%
$I_C/I_F$ ( $I_F=\pm 10 \text{ mA}$ )	30 (>13)	45 (>22)	70 (>34)	%
Collector-emitter Leakage Current, $I_{CEO}$ $V_{CE}=10 \text{ V}$	2.0 ( $\leq 50$ )	2.0 ( $\leq 50$ )	5.0 ( $\leq 100$ )	nA

**Figure 1. Current Transfer Ratio (typ.) vs. Temperature**

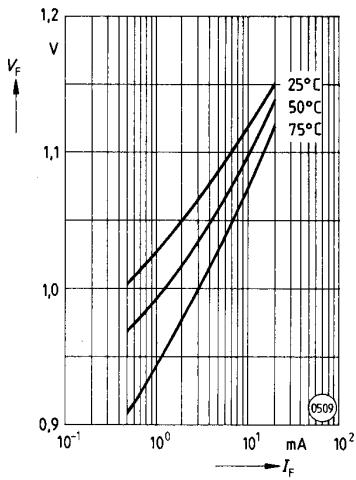
$I_F=10 \text{ mA}$ ,  $V_{CE}=5.0 \text{ V}$



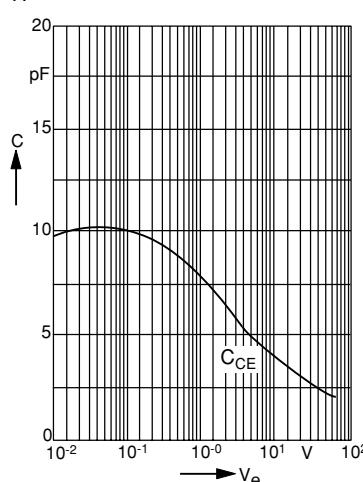
**Figure 2. Output Characteristics (typ.) Collector Current vs. Collector-emitter Voltage  $T_A=25^\circ\text{C}$**



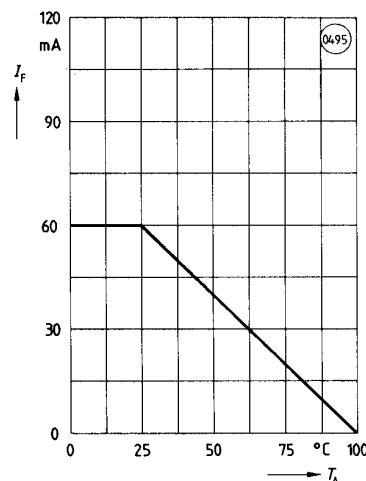
**Figure 3. Diode Forward Voltage (typ.) vs. Forward Current**



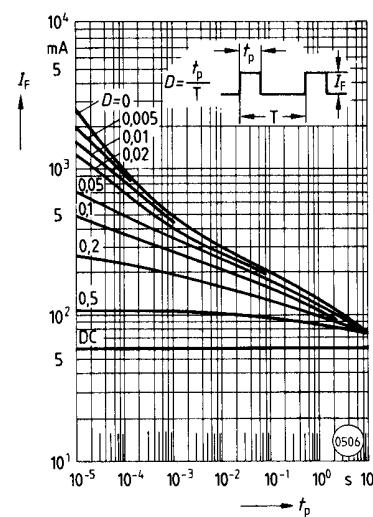
**Figure 4. Transistor Capacitance (typ.) vs. Collector-emitter Voltage  $T_A=25^\circ\text{C}$ ,  $f=1.0 \text{ MHz}$**



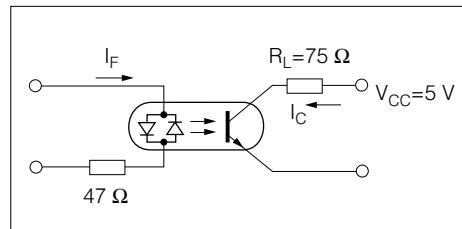
**Figure 7. Permissible Diode Forward Current vs. Ambient Temperature**



**Figure 5. Permissible Pulse Handling Capability. Fwd. Current vs. Pulse Width**  
Pulse cycle D-parameter,  $T_A=25^\circ\text{C}$



**Figure 8. Switching Times Linear Operation (without saturation)**



$I_F=10 \text{ mA}$ ,  $V_{CC}=5.0 \text{ V}$ ,  $T_A=25^\circ\text{C}$

Load Resistance	$R_L$	75	$\Omega$
Turn-on Time	$t_{on}$	3.0	$\mu\text{s}$
Rise Time	$t_r$	2.0	$\mu\text{s}$
Turn-off Time	$t_{off}$	2.3	$\mu\text{s}$
Fall Time	$t_f$	2.0	$\mu\text{s}$
Cut-off Frequency	$F_{CO}$	250	kHz

**Figure 6. Permissible Power Dissipation vs. Ambient Temperature**

